TEST SYSTEM FOR MLR1 and ER2 CHIPLETS

MLR1: First submission of MAPS in 65 nm. Used to validate the 65 nm technology (2021-2023). Three types of Test Structures (TS) characterized: APTS (Analog Pixel Test Structures), DPTS (Digital Pixel Test Structures), CE65 (Circuit Exploratoire 65 nm).

APTS: 4×4 matrix, 10-25 µm pixel, w/o process modification, analog readout

DPTS: 32×32 matrix, 15 μ m pixel, modified with gaps, digital readout, time-encoded signal amplitude and position

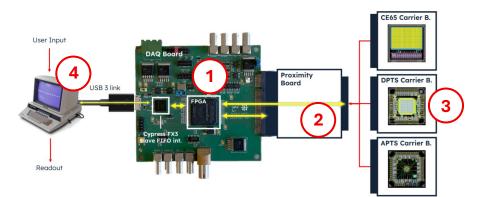
CE65: Rolling shutter readout, 3 submatrices, both amplifier and source-follower output buffers.

ER2: Production of MOSAIX, babyMOSAIX and chiplets. List of chiplets:

R2 Chiplets	5		
1 TT51 3 TT52		Process monitoring and modeling Process monitoring and modeling	Evolution of MLR1 test structures in view of ALICE 3 upgrade
5 APTS - SF standard	15 um pitch	Sensor reference	
6 APTS - SF modified	15 um pitch	Sensor reference	
7 APTS - SF modified with gap	15 um pitch	Sensor reference/optimization	APTS SF:
8 APTS - SF modified with gap	20 um pitch	Exploration of larger pixel pitches/optimization	APTS SF:
9 APTS - SF modified with gap	30 um pitch	Exploration of larger pixel pitches/optimization	 Several size implemented (20-50µm)
10 APTS - SF modified with gap	40 um pitch	Exploration of larger pixel pitches/optimization	• Several size implemented (20-30µm)
11 APTS - SF modified with gap	50 um pitch	Exploration of larger pixel pitches/optimization	 Study maximum pixel pitch
12 APTS - SF modified with gap and Nwell	50 um pitch	Study of impact of Nwell.	
13 APTS - SF modified with gap	20.8 x 22.8 um pitch	Sensor pitch in MOSAIX/optimization	 Study radiation tolerance of different splits
14 APTS - OA modified with gap	10 um pitch	Sensor reference/optimization	
15 DPTS modified with gap	15 um pitch	Sensor + FE reference/optimization	
16 DPTS modified with gap	15 um pitch	Sensor + FE reference/optimization	Variant with same pitch of MOSAIX: could
17 DPTS modified with gap	15 um pitch	Sensor + FE reference/optimization	give hint on split selection
18 SEU 3		Custom cell libraries SEE/SEL characterization	
19 RING-OSC-v1 ported		Custom cell libraries leakage and delay	APTS OA:
20 RING-OSC-v2		Custom cell libraries leakage and delay	Charge collection time and time recolution of
		Standalone qualification of other versions of DAC	 Charge collection time and time resolution of
21 MOSAIX BIASING		and biasing blocks as backup	different splits
22 MOSAIX SERIALIZER		Full chain serializer test chip as in MOSAIX	
			DPTS:
23 TDC HEIDELBERG		TDC	 Sensor + FE reference
24 IPHC ASYNCH READOUT (SPARC)		architecture study	
25 SLAC NAPA-v2		update on pulsed readout	
26 BNL ADC		Special architecture for monitoring ADC	
27 BNL Data transmission		Test chip for transmission without repeater	Same test system as MLR1, testing plan not yet
28 Bandgap/Tmonitoring		Test chip Bgap/Tmon as in MOSAIX	
			prepared

<u>SETUP</u>: Same test system for MLR1 and ER2 chiplets.

DAQ (1) + Proximity (depending on the specific test structure under test) (2) + carrier with the test structure bonded (3) + computer + power supply (4)



COST ESTIMATION:

• DAQ: provided by CERN

- Proximity: ~ 1000 CHF
- Computer: for example HP Elite Mini 800 G9 Desktop PC 5M981EA#ABZ (i7) ~ 1200 euro
- Power supply: R&S®NGC100 Power supply series ~ 1200 EUR

REFERENCE PUBLICATIONS:

- DPTS: <u>https://doi.org/10.1016/j.nima.2023.168589</u>
- APTS-SF: <u>https://doi.org/10.1016/j.nima.2024.169896</u>
- APTS-OA: https://doi.org/10.1016/j.nima.2024.170034

RECENT SUMMARY OF ITS3 CHARACTERISATION ACTIVITIES @ INFN:

https://agenda.infn.it/event/46163/

TEST SYSTEM FOR BABY-MOSAIX (ER2)

				AL:
Item		Unit price (CERN via EDH)	Reference	
1a	FPGA module	666,60 CHF	Enclustra ME-AA1-270-3E4-D11E-NFX3	
1b	FPGA module rework	200,00 CHF	Enclustra-provided BoM & placement	
1c	Heat sink	29,70 CHF	Enclustra ACC-HS4-SET	
2	Base board	289,30 CHF	Enclustra ME-ST1-W	
3	(baby)MOSAIX carrier	-	Design: A. Junique / J. Morant	
4	Power supply (2x)	1241,00 EUR	Rhode & Schwarz NGC103	
Dist	tribution and supp			

With respect to small TS test system, you need a FPGA module + rework (1), an Enclustra board (2), the carrier (3) and an additional power supply (4) $\rightarrow \sim +2500$ euro